

Notice of References Cited	Application/Control No. 09/931,131	Applicant(s)/Patent Under Reexamination KIM ET AL.	
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	B	US-6,212,669	04-2001	Jain, Jawahar	716/7
	C	US-6,086,626	07-2000	Jain et al.	716/5
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	K	US-			
	L	US-			
	M	US-			

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	U	Ravi, K. et al., "Approximating and decomposition of binary decision diagrams", 6/1998, ACM, pgs. 1-6.
	V	Yang et al., "BDS: A BDD-based logic optimization system", 6/2000, ACM, pgs. 92-97.
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	X	Chakrabarti et al., "Synthesis of symmetric functions for path-delay fault testability", 9/2000, IEEE, pgs. 1076-1081.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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